

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10550009	CHEN ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	KAMRAN AFSHAR	2617

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
455	450-453, 422.1-425, 428, 445, 560-561, 550.1, 517	9/16/2007	KA
370	328, 338, 395.1, 395.52, 351-356, 401, 386	9/16/2007	KA

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East Search (US-PGPUB; USPAT; EPO; DERWENT; IBM TDB)	9/16/2007	KA
William Trost	9/16/2007	KA
Ferris Derric	10/22/2007	KA
George Eng, Charls Appiah (Double patenting)	10/22/2007	KA
Updated East Search	12/11/2007	KA
Updated East Search	4/22/2008	KA
John Peng, 101 and new matter	4/22/2008	KA
John Peng, 101 and new matter	11/6/2008	KA
Updated East Search	11/10/2008	KA
Updated East Search	1/16/2009	KA
George Eng, New Matter	1/16/2009	KA
Updated East Search	3/17/2009	KA

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
East	Text Search	3/17/2009	KA

	/K. A./ Primary Examiner.Art Unit 2617
--	---